


LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary) 	ATTY. DOCKET NO. 618-940	APPLICATION NO. 09/865,508
	APPLICANT Richard M. ORAZIETTI	
	FILING DATE May 29, 2001	GROUP 9743-2834

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	TRADE MARK	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TMD	BC	5,417,571	05/1995	Kvalseth	431	153	
TMD	BD	5,417,563	05/1995	Cirami	431	153	
TMD	BE	5,262,697	11/1993	Meury	310	339	
TMD	BF	5,240,408	08/1993	Kenjiro et al.	431	153	
TMD	BG	5,215,458	06/1993	Cirami	431	277	
TMD	BH	5,178,532	01/1993	Frigiere	431	254	
TMD	BI	5,171,143	12/1992	Sohn	431	153	
TMD	BJ	5,125,829	06/1992	McDonough et al.	431	255	
TMD	BK	5,092,764	03/1992	McDonough et al.	431	277	
TMD	BL	5,059,852	10/1991	Meury	310	339	
TMD	BM	5,035,608	07/1991	Parren	431	153	
TMD	BN	5,002,482	03/1991	Fairbanks et al.	431	277	
TMD	BO	4,830,603	05/1989	Cirami	431	153	
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							YES	NO
TMD	BX	6-249438	09/1994	Japan	F23Q	2/28	X	
TMD	BY	60-89625	05/1985	Japan	F23Q	2/28	X	

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EXAMINER <i>Thomas M. Dougherty</i>	DATE CONSIDERED <i>2-14-03</i>
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TMB	AA	6,116,892	09/2000	Yang	431	153	
TMB	AB	6,106,277	08/2000	Xie	431	153	
TMB	AC	6,102,689	08/2000	Man	431	153	
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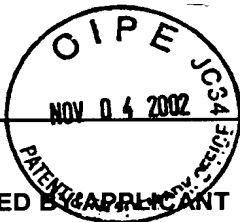
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3743-2837

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TMK	AA	US 2002/0136996	9/26/02	Ichikawa et al.	431	153	
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	AD						
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TMK	AK	JP 2001-343122	12/14/01	Japan w/Eng. Abstract	F23Q	2/28	abs	
	AL							
	AM							
	AN							

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	AP	
	AQ	

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